

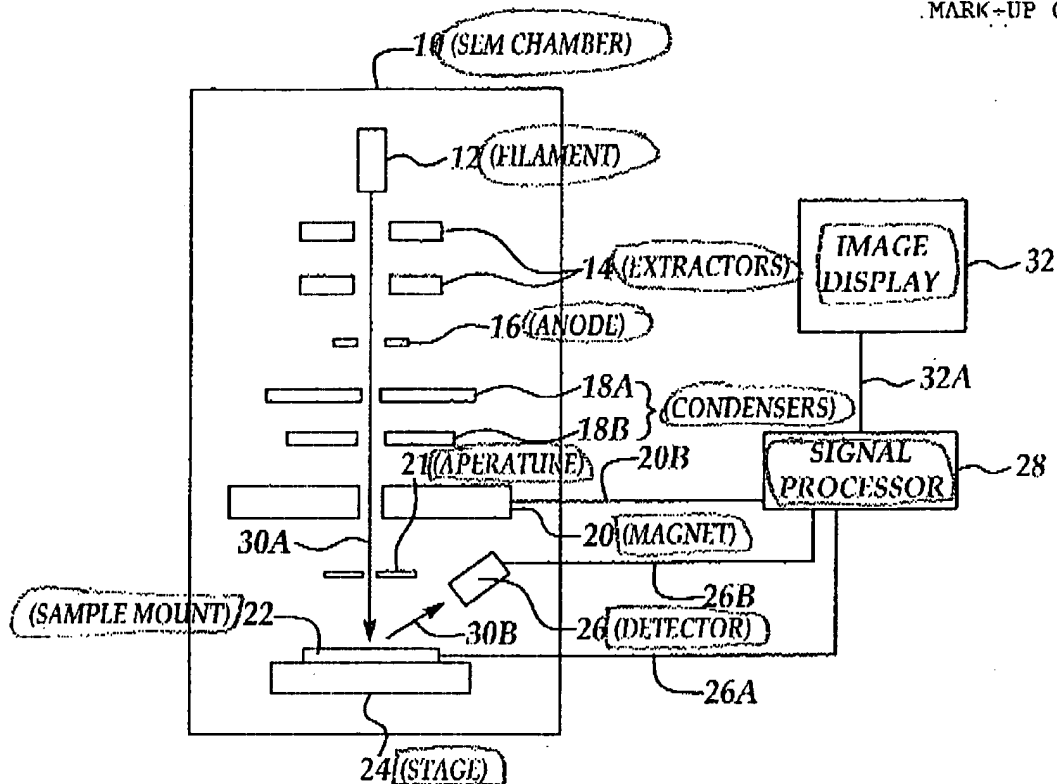
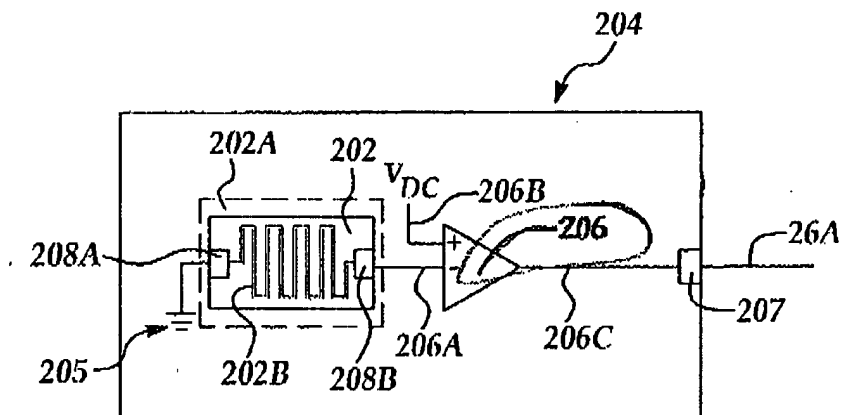
Inventor: Hui-Chuan Hung

Serial No.: 10/656,754 Filed: 09/06/2003

For: In-Situ Electron Beam Induced Current Detection

Attorney Doc. No.: 67,200-1152

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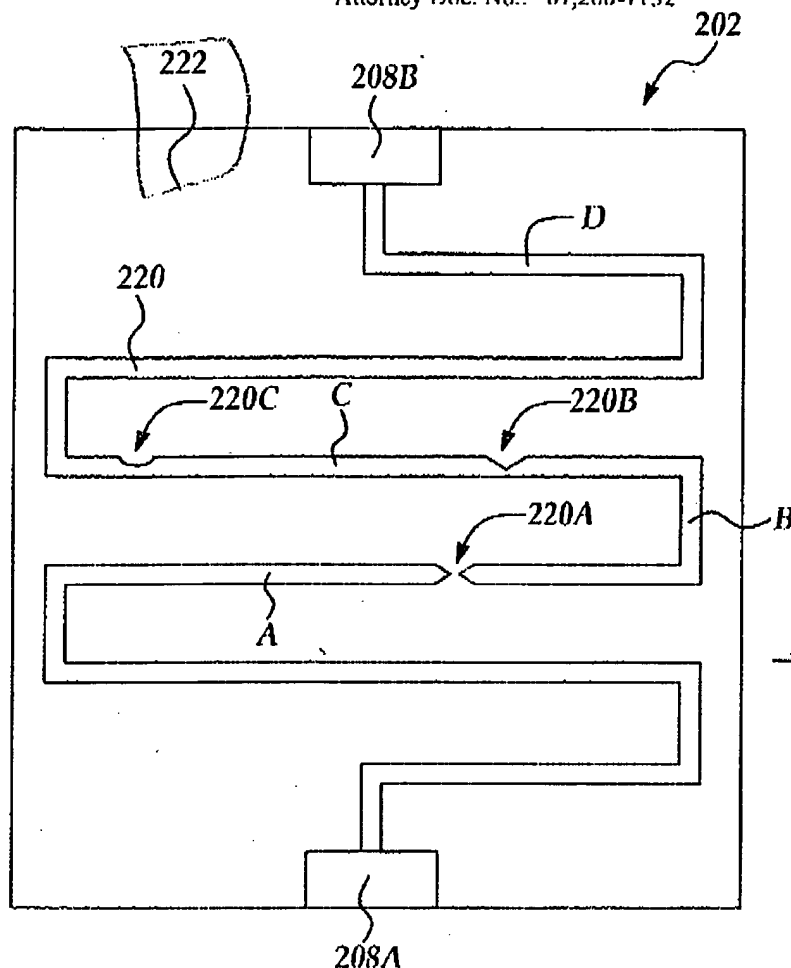
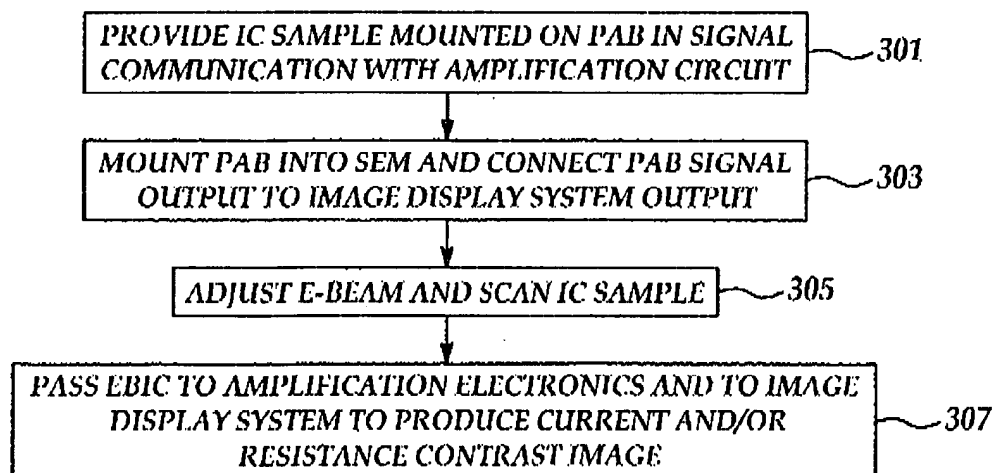
Figure 1Figure 2A

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Figure 2BFigure 3

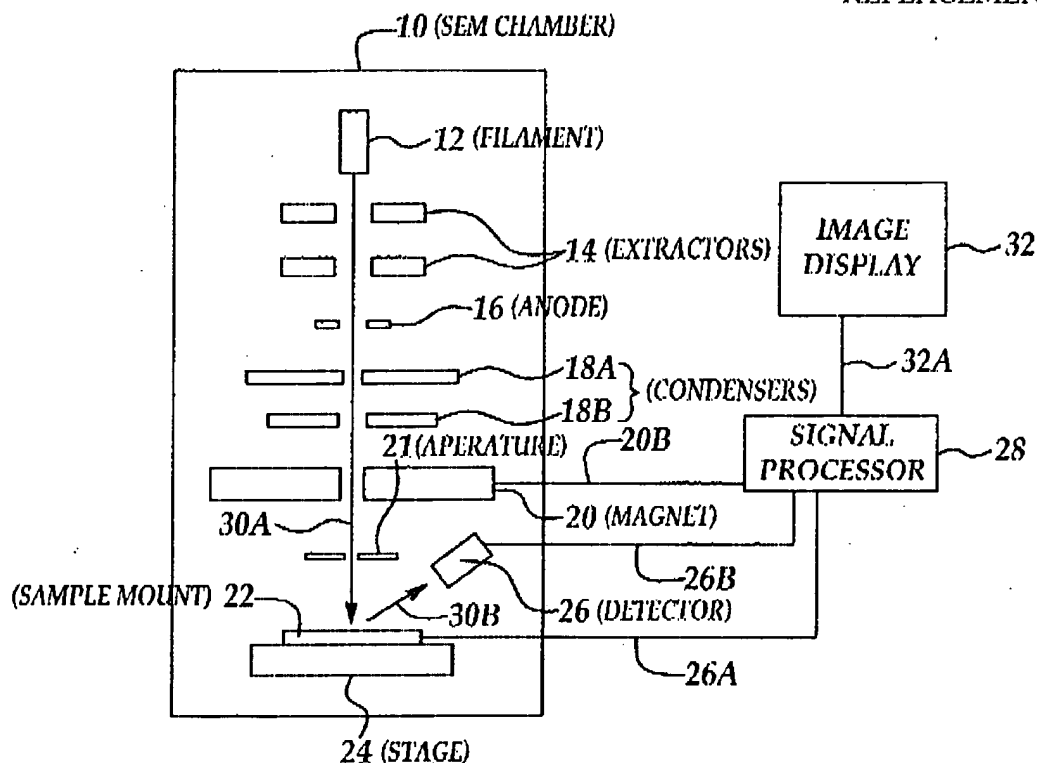
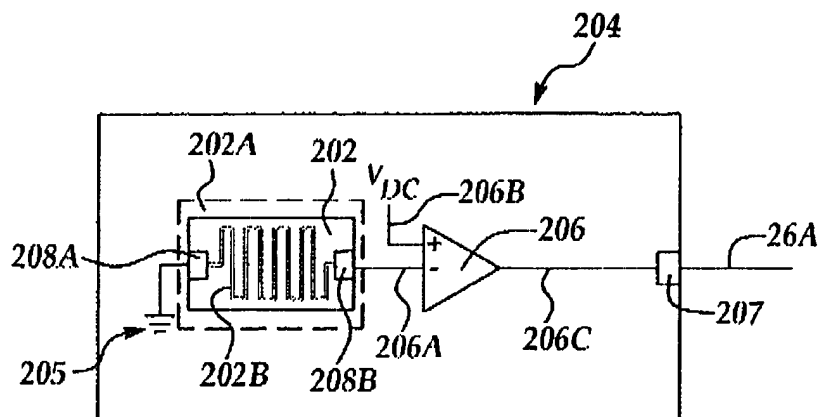
Inventor: Hui-Chuan Hung

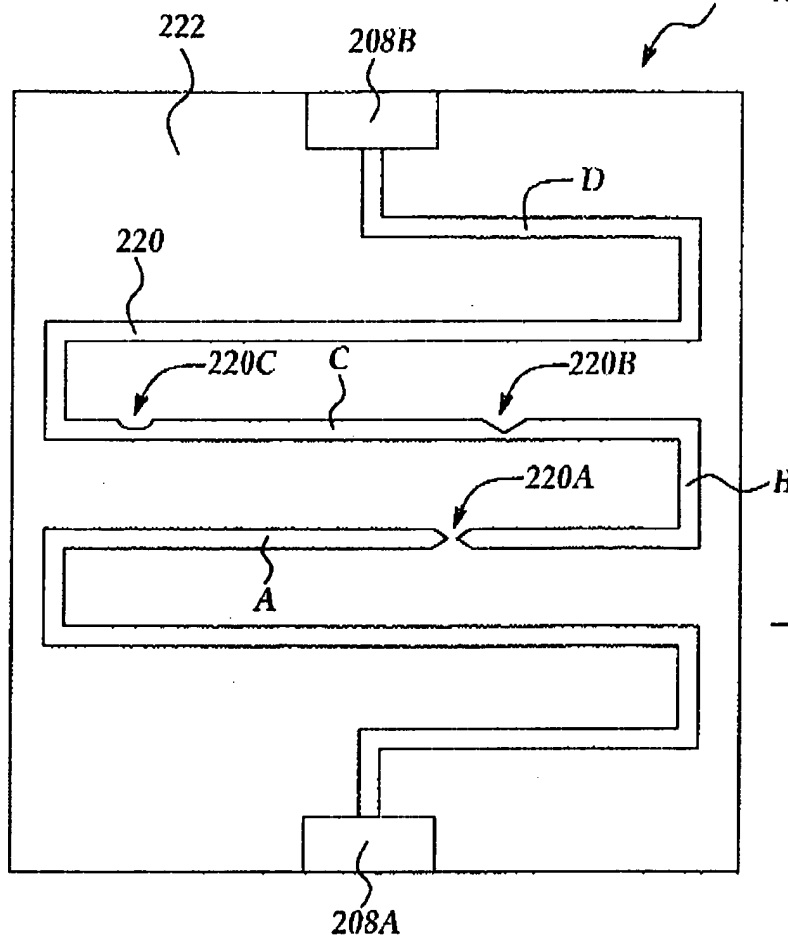
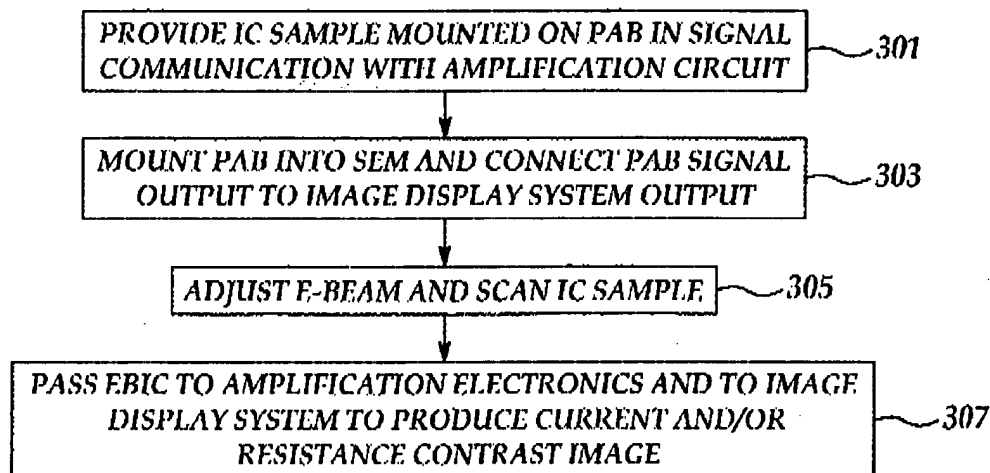
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REPLACEMENT SHEET

Figure 1Figure 2A

Figure 2BFigure 3